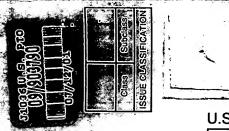

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APPLICATION NO. 09/903790	CONT/PRIOR F	CLASS 382 438 446	SUBCLASS	ART UNIT 2 2 2 3	EXAMINER J. Maneuro
Ryoichi M	atsuoka				Virginia Kibber

Navigation method and device for pattern observation of semiconductor device $% \left(1\right) =\left(1\right) \left(1$

(Attached in pocket on right inside flap)

	ISSUING CLASSIFICATION							
ORIGINAL			CROSS REFERENCE(S)					
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INTERNATIONAL CLASSIFIC	CATION							
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4.	DRAWINGS		CLAIMS ALLOWED		
Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.	
	*		NOTICE OF ALLOWANCE MAILE		
(Assistant I	Examiner)	(Date)			
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tricted. Unauthorized on nark Office is restricted	disclosure may be p to authorized emplo	prohibited by the U	Inited States Code Title 3 tors only.	5, Sections 122, 181 and 366	
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